

ITW

PATENT
3511-1033

IN THE U. S. PATENT AND TRADEMARK OFFICE

In re application of

Liro HIETANEN et al.

Conf. 6321

Application No. 10/533,645

Group 2877

Filed: January 13, 2006

Examiner Rebecca Slomski

Title: SYNCHRONOUS OPTICAL MEASUREMENT
AND INSPECTION METHOD AND MEANS

AMENDMENT

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

March 28, 2008

Sir:

In response to the Office Action mailed December 28, 2007, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins 2 of this paper.

Remarks begin 12 of this paper.